

# AIS-Q574

(With 3.5" SATA H.D)

## Environment Test Report

Report NO: 11I020008

Summary	<p><input type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input checked="" type="checkbox"/> Pass with Deviation</p> <p>Comment: <u>Under PassMark Burn In Test 6.0 Pro, test COM port baud rate 115200 test fail , but change to 9600 test pass.</u></p>
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Issue date

Approval

Test Engineer

2011-05-11

Jansin Lee

Clement Chien

## Test item list

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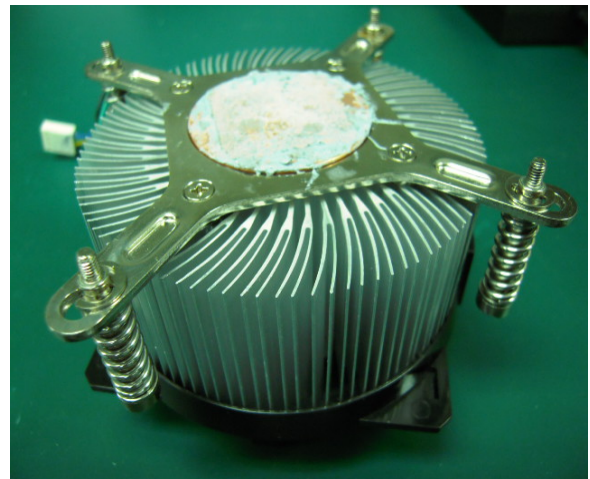
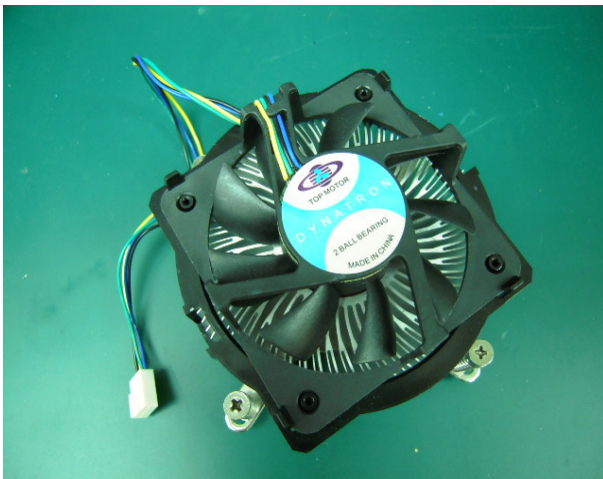
### Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

# Configuration of EUT

Num	Item	Spec
1.	<b>System:</b>	AIS-Q574
	1. Main Board	IMBI-QM57 A1.0 (BIOS Ver: AIS-Q574 0.01 X64)
	2. CPU	Intel Core i7-860 Processor 2.80 GHz
	3. Memory	DSL 4GB*2 / DDR3 1333 CL9 / ELPIDA J2108BCSE-DJ-F
	4. 3.5" SATA HDD	Seagate ST3160811AS/160GB
	5. Test Software	Windows XP / Run PassMark Burn In Test 6.0 Pro
	6.VGA Card	ASUS EAX1600PRO/TD/256M/A(ATI Chipset)
	7.CD-ROM	Optiarc DVD RW AD-7585H
2.	ATX Power Supply	CWT PSM275H 275W

## CPU Cooler



# Temperature rise test

**Test Date:** 04-11-2011

**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100-13-1D

Date of Calibration: 11/08/2010

Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 45°C

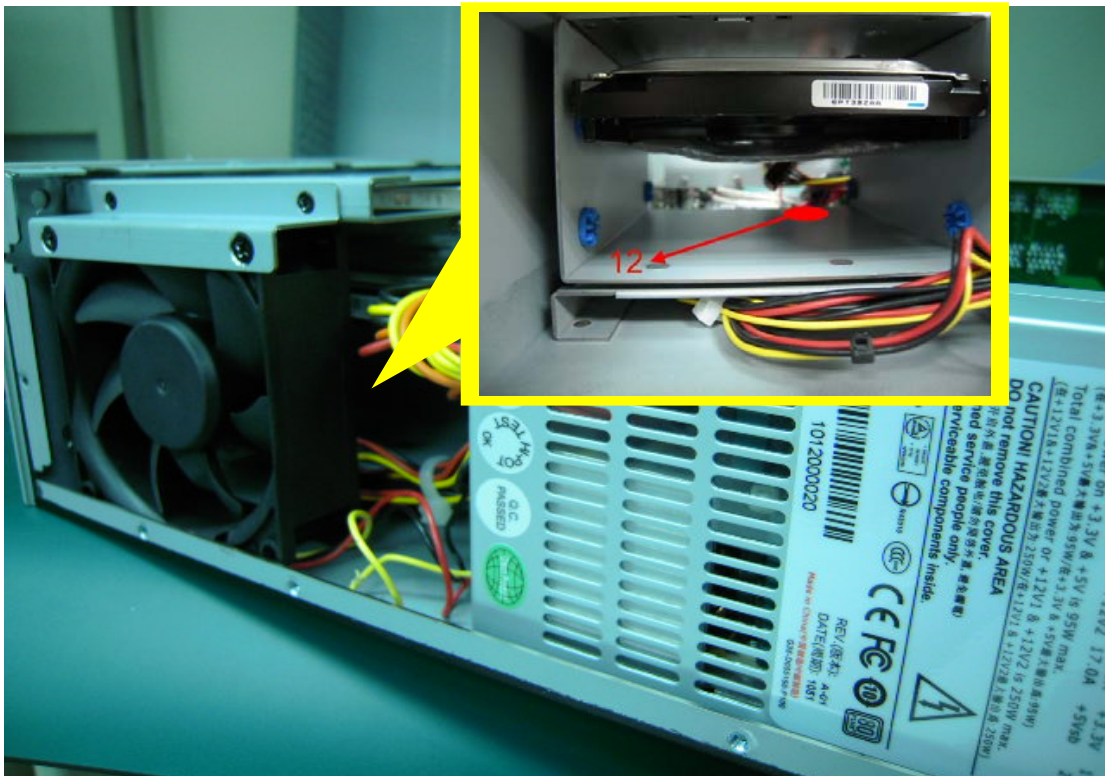
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

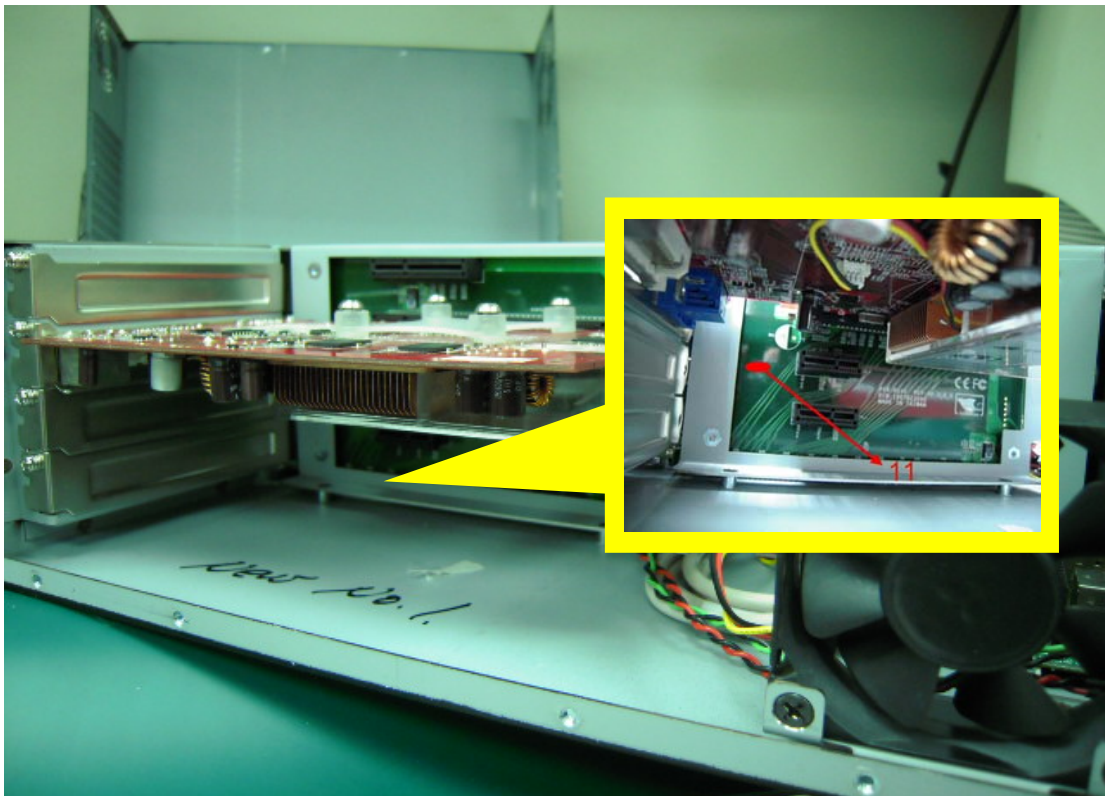
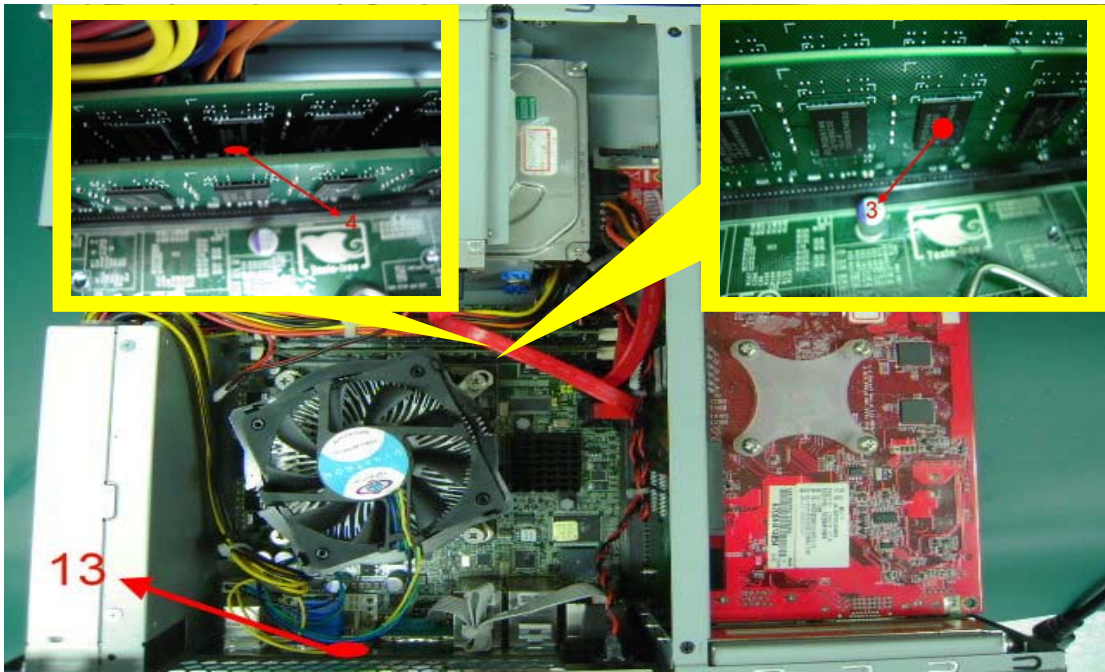
Windows XP / Run PassMark Burn In Test 6.0 Pro

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Temperature rise test



# Temperature rise test

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# Temperature rise test

## Thermal profile data:

### AIS-Q574

Point	Temp. Stage(°C)	Spec	45	25
<b>IMBI-QM57</b>				
01. CPU - Intel Core i7-860 Processor 2.80GHz		72.7	69.6	49.6
02. U13 - (TF)Chipset Ibex Peak PCH951P.INTEL.BD82Q57,SLGZW		111	65.0	45.0
03. RAM - DSL DDR3 / 1333 / 4GB CL9		95	60.2	40.2
04. RAM - DSL DDR3 / 1333 / 4GB CL9		95	61.0	41.0
05. SATA H.D - Seagate ST3160811AS 160GB		60	49.1	29.1
06. U15 - (TF) Super I/O.ITE.IT8718F/HX-L		100	64.9	44.9
07.U19 - (TF) 7.1Channel HDAudio Codec.REALTEK.ALC888-VC2-GR		100	66.7	46.7
08.U18 - (TF)GigaBit Ethernet Chipset.Intel.WG82574L.WG82574L SLBA8		109	64.6	44.6
09.U20 - (TF)SPI Bus Serial EEPROM.ATMEL.AT25080AN-10SU-2.7		115	63.7	43.7
10.U12. -(TF) 4Phase PWM Controler.Intersil.ISL6334CRZ		100	64.7	44.7
11. Control Box Inside Air Temperature		N/A	52.1	32.1
12. Control Box Inside Air Temperature		N/A	45.9	25.9
13. Control Box Inside Air Temperature		N/A	60.4	40.4
14. Control Box Surface Temperature		N/A	51.6	31.6
15. Chamber Air Temperature		N/A	45.1	25.1
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>				

## Temperature Measurement Table:

Location	TA=45.0°C	Temp. Rise (Thermal Couple)	SpeedFan 4.42 (Read from BIOS)
Sensor 1 / Temp.(CPU)		64.0°C	64.0°C
Sensor 2 / Temp1.(South Bridge)		65.0°C	61.0°C
Sensor 3 / Temp2.(System)		N/A	61.0°C

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q574)

## Test Result:

No problem was found during the temperature rise operation test.

# Temperature cycle test

**Test Date:** 04-06~08-2011

**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

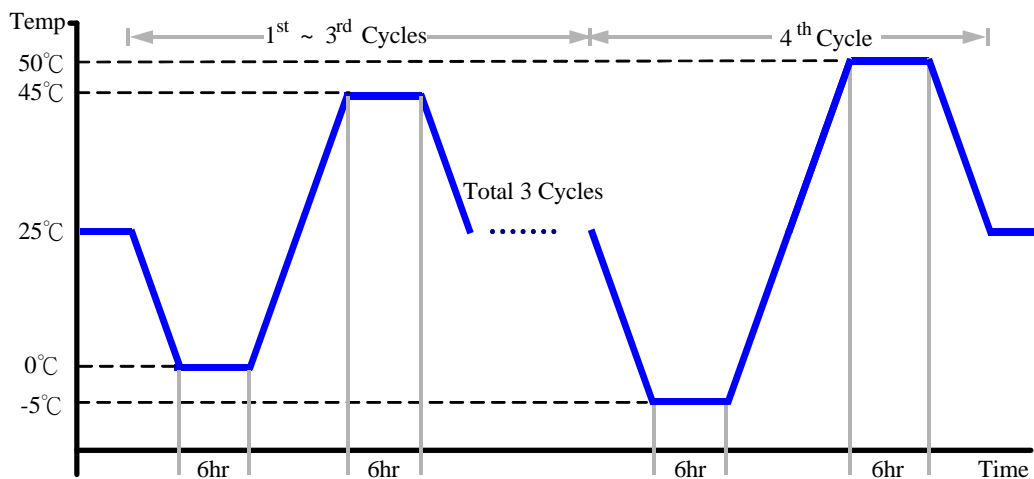
**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D75-100+LN2  
Date of Calibration: 12/02/10  
Serial Number: 6487KT

**Test Condition:**

1. Test Low Temperature: 0°C (1~3 cycles)  
-5°C (4<sup>th</sup> cycle)
2. Test High Temperature: 45°C (1~3 cycles)  
50°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q574)

**Test Result:**

No problem was found during the temperature operation cycle test.



# High temperature storage test

**Test Date:** 03-30-2011 ~ 04-01-2011

**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

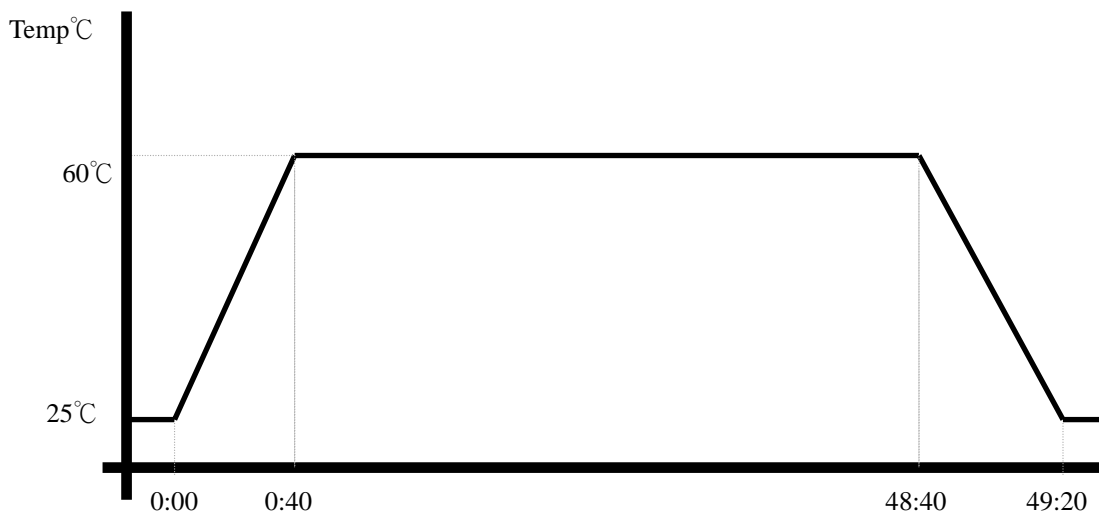
Model: THS-D75-100+LN2

Date of Calibration: 12/02/10

Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q574)

**Test Result:**

No problem was found after the high temperature storage test.

# Low temperature storage test

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**Test Date:** 03-28~30-2011

**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

Date of Calibration: 12/02/10

Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q574)

**Test Result:**

No problem was found after the low temperature storage test.

# Humidity test

**Test Date:** 04-03~05-2011

**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

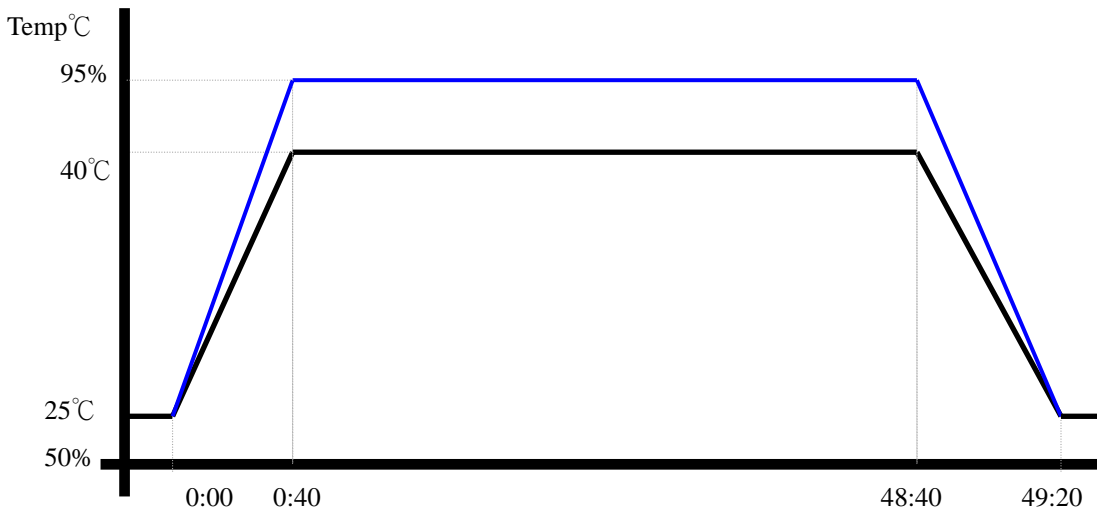
Date of Calibration: 12/02/10

Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
5. Test Environment Curve:

**Humidity %**



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q574)

**Test Result:**

No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 04-05~06-2011

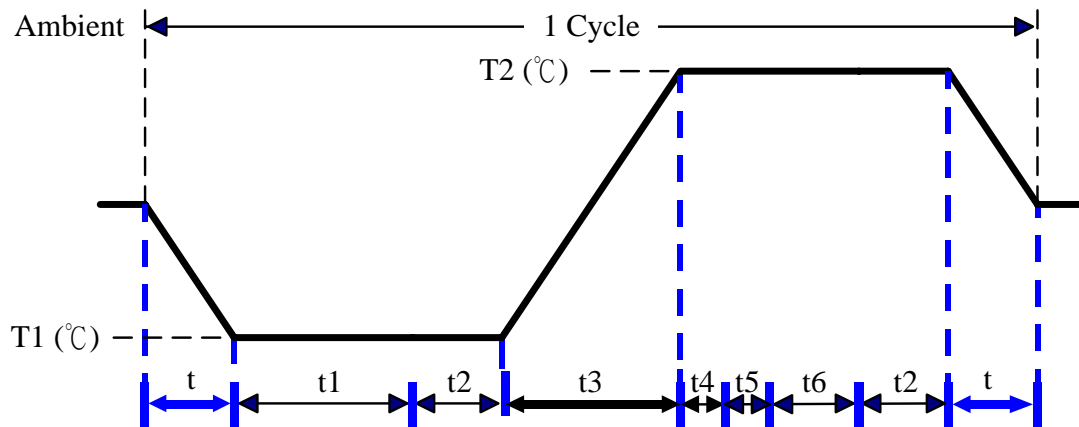
**Test Product:** AIS-Q574

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
 Programmable Temperature & Humidity Chamber  
 K.SON. INS. TECH. CORP.  
 Model: THS-D75-100+LN2  
 Date of Calibration: 12/02/10  
 Serial Number: 6487KT

**Test Condition:**



Parameters	Description
T1	-5°C
T2	50°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temperature slope  
 t, t1, t6: Power Off  
 t2: Power on/off test 10 times (on 2 min / off 5min)  
 t3, t4: Run PassMark Burn In Test  
 t5: Win XP Software restart test 3 times  
 Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.